### **CE EMC**

# **TEST REPORT**

#### For

## Industrial Flat Panel Monitor with 17" LCD in VGA

Model: FPM-3171GX-X (First  $X = A \sim Z$  or Blank; Second X = C, R or Blank)

**Trade Name: ADVANTECH** 

#### Issued for

Advantech Co., Ltd. No. 1, Alley 20, Lane 26, Rueiguang Road, Neihu District, Taipei 114, Taiwan, R.O.C.

Issued by

Compliance Certification Services Inc. No. 81-1, Lane 210, Bade Rd., 2, Luchu Hsiang, Taoyuan Hsien, (338) Taiwan, R.O.C.

TEL: 886-3-324-0332 FAX: 886-3-324-5235



Date of Issue: January 6, 2005

Note: This report shall not be reproduced except in full, without the written approval of Compliance Certification Services Inc. Ltd. This document may be altered or revised by Compliance Certification Services Inc. personnel only, and shall be noted in the revision section of the document.

# TABLE OF CONTENTS

1	TES	ST RESULT CERTIFICATION	3
2	EU'	T DESCRIPTION	Δ
3	TES	ST METHODOLOGY	5
	3.1 3.2	EUT SYSTEM OPERATION DECISION OF FINAL TEST MODE	5
4	SE	ΓUP OF EQUIPMENT UNDER TEST	<i>6</i>
5	FA	CILITIES AND ACCREDITATIONS	<i>6</i>
	5.1 5.2	FACILITIESLABORATORY ACCREDITATIONS AND LISTINGS	
6	INS	STRUMENT AND CALIBRATION	8
	6.1 6.2	MEASURING INSTRUMENT CALIBRATION	
7	LIN	NE CONDUCTED & RADIATED EMISSION TEST	11
	7.1 7.2 7.3	LIMIT TEST PROCEDURE OF LINE CONDUCTED EMISSION TEST PROCEDURE OF COMMON MODE CONDUCTED EMISSION FOR	12
	7.4 7.5	TELECOMMUNICATION PORT TEST PROCEDURE OF RADIATED EMISSION TEST RESULTS	14
8	PO	WER HARMONICS TEST	19
9	PO	WER VOLTAGE FLUCTUATION / FLICKER TEST	21
10	ELI	ECTROSTATIC DISCHARGE (ESD) IMMUNITY TEST	23
11	RA	DIATED ELECTROMAGNETIC FIELD IMMUNITY TEST	29
12	FAS	ST TRANSIENTS/BURST IMMUNITY TEST	32
13	SU	RGE IMMUNITY TEST	34
14		NDUCTED DISTURBANCE/INDUCED RADIO-FREQUENCY FIELD MUNITY TEST	36
15	PO	WER FREQUENCY MAGNETIC FIELD IMMUNITY TEST	38
16	VO	LTAGE DIPS / SHORT INTERRUPTIONS	40
ΑP	PENI	DIX I - PHOTOGRAPHS OF TEST SETUP	42
AP	PENI	DIX II – TEST RESULT OF EN 61000-3-3	49

# 1 TEST RESULT CERTIFICATION

**Applicant:** 

Advantech Co., Ltd.

No. 1, Alley 20, Lane 26, Rueiguang Road, Neihu District,

Date of Issue: January 6, 2005

Taipei 114, Taiwan, R.O.C.

Manufacturer:

Advantech Co., Ltd.

No. 1, Alley 20, Lane 26, Rueiguang Road, Neihu District,

Taipei 114, Taiwan, R.O.C.

**Equipment Under Test:** 

Industrial Flat Panel Monitor with 17" LCD in VGA

**Trade Name:** 

**ADVANTECH** 

Model:

FPM-3171GX-X

(First  $X = A \sim Z$  or Blank; Second X = C, R or Blank)

**Detailed EUT Description:** 

See Item 2 of this report

Date of Test:

January 3, 2005

<b>Applicable Standard</b>	Class/Limit/Criterion	Test Result
EN 55022: 1998	Class B	No non-compliance noted
EN 61000-3-2: 2000	Class A/B/C/D	N/A
EN 61000-3-3: 1995 + A1: 2001	Limit	No non-compliance noted
EN 55024: 1998 + A1: 2001, including		2 1
IEC 61000-4-2: 1995 + A2: 2000	Criterion B	No non-compliance noted
IEC 61000-4-3: 1995 + A2: 2000	Criterion A	No non-compliance noted
IEC 61000-4-4: 1995 + A1: 2000	Criterion B	No non-compliance noted
IEC 61000-4-5: 1995 + A1: 2000	Criterion B	No non-compliance noted
IEC 61000-4-6: 1996 + A1: 2000	Criterion A	No non-compliance noted
IEC 61000-4-8: 1993 + A1: 2000	Criterion A	No non-compliance noted
IEC 61000-4-11: 1994 + A1: 2000	Criterion B/C/C	No non-compliance noted
Deviation	from Applicable Standard	
	None	

The above equipment was tested by Compliance Certification Services Inc. for compliance with the requirements set forth in the EMC Directive 89/336/EEC and the technical standards mentioned above. The results of testing in this report apply only to the product/system, which was tested. Other similar equipment will not necessarily produce the same results due to production tolerance and measurement uncertainties.

Approved by:

Kurt Chen

Director of Linkou Laboratory

Compliance Certification Services Inc.

Reviewed by:

Susan Su

Section Manager of Linkou Laboratory

Compliance Certification Services Inc.

# 2 EUT DESCRIPTION

Product	Industrial Flat Panel Monitor with 17" LCD in VGA				
Trade Name	ADVANTECH				
Model	FPM-3171GX-X (First $X = A \sim Z$ or Blank; Second $X = C$ , R or Blank)				
Housing Type	Metal Case				
<b>EUT Power Rating</b>	DCV from Power Adapter				
Power Adapter Manufacturer	LIEN Electronics	Model	LE-9702B + 5012		
Power Adapter Power Rating	I/P: 100-240VAC, 50-60Hz, 1.5A O/P: 12VDC, 4.16A				
AC Power Cord Type	Unshielded, 1.8m (De	tachable)			
DC Power Cable Type	Unshielded, 1.8m (Non-detachable) at Power Adapter with a core				
OSC/Clock Frequencies	24.576MHz				
LCD Panel Manufacturer	Fujitsu	Model	FLC48SXC8V		

Date of Issue: January 6, 2005

#### I/O PORT OF EUT

I/O PORT TYPES	Q'TY	TESTED WITH
1). Serial Port	1	1
2). Video Port (VGA)	1	1

**Note:** 1. The means of "X" (First  $X = A \sim Z$  or Blank; Second X = C, R or Blank) on model number are list as below:

Suffix	Difference					
First X	Customize Version 0-9, A-Z or Blank Marketing purpose					
		Blank	Without Touch Screen			
Second X	Touch Screen Function	R	With Resistor Touch Screen			
		C	With Capacity Type Touch Screen			

2. Client consigns only one model sample to test (Model Number: FPM-3171GA-R). Therefore, the testing Lab. just guarantees the unit, which has been tested.

Page 4 Rev. 00

# 3 TEST METHODOLOGY

#### 3.1 EUT SYSTEM OPERATION

- 1. EMI test program was loaded and executed in Windows XP mode.
- 2. Data was sent to EUT filling the screen with upper case of "H" patterns.
- 3. Test program sequentially exercised printer and modem, and then sent "H" patterns to them individually.

Date of Issue: January 6, 2005

4. Repeat 2 to 3.

*Note:* Test program is self-repeating throughout the test.

#### 3.2 DECISION OF FINAL TEST MODE

1. The following test mode(s) were scanned during the preliminary test:

#### Mode 1

 $1280 \times 1024$  Resolution

#### Mode 2

 $1024 \times 768$  Resolution

#### Mode 3

 $800 \times 600$  Resolution

2. After the preliminary scan, the following test mode was found to produce the highest emission level.

Mode 1

Then, the EUT configuration and cable configuration of the above highest emission mode was chosen for all final test items.

Page 5 Rev. 00

# 4 SETUP OF EQUIPMENT UNDER TEST

#### Setup Diagram

See test photographs attached in Appendix 1 for the actual connections between EUT and support equipment.

Date of Issue: January 6, 2005

#### **Support Equipment**

No.	Equipment	Model No.	Serial No.	FCC ID	Trade Name	Data Cable	Power Cord
1	PC	Dimemsion 4600	1Q14B1S	FCC DoC	DELL	VGA Cable: Shielded, 1.8m with two cores RS232 Cable: Shielded, 1.8m	Unshielded, 1.8m
2	Printer	STYLUS C60	DR3K039425	FCC DoC	EPSON	Shielded, 1.8m	Unshielded, 1.8m
3	PS/2 Keyboard	Y-SP29	SYU30272817	FCC DoC	Logitech	Shielded, 1.8m	N/A
4	PS/2 Mouse	M-CAA43	LZE03262922	FCC DoC	Logitech	Shielded, 1.8m	N/A

**Note:** All the above equipment/cables were placed in worse case positions to maximize emission signals during emission test.

**Grounding:** Grounding was in accordance with the manufacturer's requirements and conditions for the intended use.

# 5 FACILITIES AND ACCREDITATIONS

#### **5.1 FACILITIES**

All measurement facilities used to collect the measurement data are located at CCS Taiwan Linkou Lab at No. 81-1, Lane 210, Bade Rd., 2, Luchu Hsiang, Taoyuan Hsien, Taiwan.

The measurement facilities are constructed in conformance with the requirements of CISPR 16-1, ANSI C63.4 and other equivalent standards.

Page 6 Rev. 00

#### 5.2 LABORATORY ACCREDITATIONS AND LISTINGS

The test facilities used to perform Electromagnetic compatibility tests are registered or accredited by the organizations listed in the following table which includes the recognized scope specifically.

Date of Issue: January 6, 2005

Country	Agency	Scope of Accreditation	Logo
USA	NVLAP	EN 55011, EN 55014-1, AS/NZS 1044, CNS 13783-1, EN 55022, CNS 13438, EN 61000-3-2, EN 61000-3-3, ANSI C63.4, FCC OST/MP-5, AS/NZS CISPR 22, IEC 61000-4-2, IEC 61000-4-3, IEC 61000-4-4, IEC 61000-4-5, IEC 61000-4-6, IEC 61000-4-8, IEC 61000-4-11	NVIAP Lab. Code: 200600-0
USA	FCC	3/10 meter Open Area Test Sites to perform FCC Part 15/18 measurements	FC 93105, 90471
Japan	VCCI	3/10 meter Open Area Test Sites and conducted test sites to perform radiated/conducted measurements	VCCI R-393/1066/725/879/1868 C-402/747/912
Norway	NEMKO	EN 50081-1/2, EN 50082-1/2, IEC 61000-6-1/2, EN 50091-2, EN 50130-4, EN 55011, EN 55013, EN 55014-1/2, EN 55015, EN 55022, EN 55024, EN 61000-3-2/3, EN 61326-1, IEC 61000-4-2/3/4/5/6/8/11, EN 60601-1-2, EN 300 328-2, EN 300 422-2, EN 301 419-1, EN 301 489-01/03/07/08/09/17, EN 301 419-2/3, EN 300 454-2, EN 301 357-2	ELA 124a ELA 124b ELA 124c
Taiwan	CNLA	EN 300 328-1, EN 300 328-2, EN 300 220-1, EN 300 220-2, EN 300 220-3, 47 CFR FCC Part 15 Subpart C, EN 61000-3-2, EN 61000-3-3, CNS 13439, CNS 13783-1, CNS 14115, CNS 13438, AS/NZS CISPR 22, CNS 13022-1, IEC 61000-4-2/3/4/5/6/8/11, CNS 13022-2/3	0 3 6 3 ILAC MRA
Taiwan	BSMI	CNS 13438, CNS 13783-1, CNS 13439, CNS 14115	SL2-IS-E-0014 / IN-E-0014 /A1-E-0014 /R1-E-0014 /R2-E-0014 /L1-E-0014
Canada	Industry Canada	RSS212, Issue 1	<b>Canada</b> IC 3991-3 IC 3991-4

**Note:** No part of this report may be used to claim or imply product endorsement by CNLA, NVLAP or other government agency.

Page 7 Rev. 00

#### 6 INSTRUMENT AND CALIBRATION

#### 6.1 MEASURING INSTRUMENT CALIBRATION

The measuring equipment utilized to perform the tests documented in this report has been calibrated once a year or in accordance with the manufacturer's recommendations, and is traceable under the IEC 17025 to international or national standards. Equipment has been calibrated by accredited calibration laboratories.

Date of Issue: January 6, 2005

# 6.2 TEST AND MEASUREMENT EQUIPMENT

The following list contains measurement equipment used for testing. The equipment conforms to the requirement of CISPR 16-1, ANSI C63.2 and other required standards.

Calibration of all test and measurement, including any accessories that may effect such calibration, is checked frequently to ensure the accuracy. Adjustments are made and correction factors are applied in accordance with the instructions contained in the respective manual.

#### **Equipment Used for Emission Measurement**

Conducted Emission Test Site # 3						
Name of Equipment   Manufacturer   Model   Serial Number   Calibration D						
EMI Test Receiver	R&S	ESCS30	845552/030	03/14/2005		
LISN	R&S	ESH2-Z5	843285/010	01/08/2005		
LISN	EMCO	3825/2	9003-1628	07/26/2005		

**Note:** The measurement uncertainty is less than +/- 2.83dB, which is evaluated as per the NAMAS NIS 81 and CISPR/A/291/CDV.

Open Area Test Site # 2						
Name of Equipment	Manufacturer	Model	Serial Number	Calibration Due		
Spectrum Analyzer	ADVANTEST	R3261A	21720279	N.C.R		
EMI Test Receiver	SCHAFFNER	SCR 3501	436	11/18/2005		
Pre-Amplifier	HP	8447D	2944A08780	07/14/2005		
Bilog Antenna	SCHWAZBECK	VULB9160	3065	12/11/2005		
Turn Table	Chance Most	CM-T003-1	T807-6	N.C.R		
Antenna Tower	Chance Most	CM-A003-1	A807-6	N.C.R		
Controller	Chance Most	N/A	N/A	N.C.R		
RF Switch	ANRITSU	MP59B	M76890	N.C.R		
Site NSA	CCS	N/A	N/A	08/13/2005		

**Note:** The measurement uncertainty is less than +/- 3.36dB, which is evaluated as per the NAMAS NIS 81 and CISPR/A/291/CDV.

Page 8 Rev. 00

Power Harmonic & Voltage Fluctuation/Flicker Measurement (EN 61000-3-2&-3-3)					
Name of Equipment   Manufacturer   Model   Serial Number   Calibration Du					
HARMONICS SYSTEM	EMC-PARTNER	HARMONICS-1 000	094	11/04/2005	

Date of Issue: January 6, 2005

# **Equipment Used for Immunity Measurement**

ESD Test Site (IEC/EN 61000-4-2)					
Name of Equipment Manufacturer Model Serial Number Calibration Du					
ESD Generator	EM TEST	P30C	0603-01	08/01/2005	

Radiated Electromagnetic Field Immunity Test Site (IEC/EN 61000-4-3)						
Name of Equipment	Manufacturer	Model	Serial Number	Calibration Due		
S.G.	R&S	SMY02	100094	08/05/2005		
Power Meter	R&S	NRVD	837794/029	08/06/2005		
Power Sensor	R&S	URV5-Z2	835640/015	08/06/2005		
Power Sensor	R&S	URV5-Z2	835640/016	08/06/2005		
Power Amplifier	ar	150W1000	300300	N.C.R		

Fast Transients/Burst Test Site (IEC/EN 61000-4-4)							
Name of Equipment   Manufacturer   Model   Serial Number   Calibration							
Fast Transients/Burst Generator	HAEFELY TRENCH	PEFT- JUNIOR	583 333-117	08/25/2005			

Surge Immunity Test Site (IEC/EN EN 61000-4-5)							
Name of Equipment	Manufacturer	Model	Serial Number	<b>Calibration Due</b>			
Surge Tester	HAEFELY TRENCH	PSUGER 4010	583 334-71	08/25/2005			

Page 9 Rev. 00

CS Test Site (IEC/EN 61000-4-6)							
Name of Equipment	Serial Number	<b>Calibration Due</b>					
S.G.	R&S	SMY02	100094	08/05/2005			
Power Meter	R&S	NRVD	837794/029	08/06/2005			
Power Sensor	R&S	URV5-Z2	835640/015	08/06/2005			
Power Sensor	R&S	R&S URV5-Z2		08/06/2005			
Power Amplifier	ar	500A100A	300299	N.C.R			
CDN	Lüthi	801-M3	1879	03/03/2005			
CDN	FRANKONIA	CDN-M2	A3002010	08/06/2005			

Date of Issue: January 6, 2005

Power Frequency Magnetic Field Immunity Test Site (IEC/EN 61000-4-8)								
Name of Equipment	of Equipment Manufacturer Model Serial Number Calibration							
TRIAX ELF Magnetic Field Meter	F.W.BELL	4090	9711	11/21/2005				
Magnetic Field Tester HAEFELY TRENCH		MAG 100.1	080 938-01	N.C.R				

Voltage Dips/Short Interruption and Voltage Variation Immunity Test Site (IEC/EN 61000-4-11)							
Name of Equipment Manufacturer Model Serial Number Calibration							
Dips/Interruption and Variations Simulator	HAEFELY TRENCH	PLINE 1610	080 344-05	04/06/2005			

Page 10 Rev. 00

# 7 LINE CONDUCTED & RADIATED EMISSION TEST

Date of Issue: January 6, 2005

#### **7.1 LIMIT**

#### **Maximum permissible level of Line Conducted Emission**

Frequency	Class A	(dBuV)	Class B (dBuV)		
(MHZ)	Quasi-peak	Average	Quasi-peak	Average	
0.15 - 0.5	79	66	66 - 56	56 - 46	
0.50 - 5.0	73	60	56	46	
5.0 - 30.0	73	60	60	50	

*Note:* The lower limit shall apply at the transition frequency.

# <u>Maximum permissible level of Common Mode Conducted Emission</u> (Telecommunication Ports)

## **CLASS A**

Frequency	Voltage Lii	mit (dBuV)	Current Limit (dBuA)		
(MHZ)	Quasi-peak	Average	Quasi-peak	Average	
0.15 - 0.5	97 – 87	84 - 74	53 – 43	40 – 30	
0.5 - 30.0	87	74	43	30	

*Note:* The lower limit shall apply at the transition frequency.

#### **CLASS B**

Frequency	Voltage Lii	mit (dBuV)	Current Limit (dBuA)		
(MHZ)	Quasi-peak	Average	Quasi-peak	Average	
0.15 - 0.5	84 - 74	74 - 64	40 – 30	30 – 20	
0.5 - 30.0	74	64	30	20	

*Note:* The lower limit shall apply at the transition frequency.

#### Maximum permissible level of Radiated Emission measured at 10 meter

Frequency	Class A (dBuV/m)	Class B (dBuV/m)		
(MHZ)	Quasi-peak	Quasi-peak		
30 – 230	40	30		
230 - 1000	47	37		

Note: The lower limit shall apply at the transition frequency.

Page 11 Rev. 00

#### 7.2 TEST PROCEDURE OF LINE CONDUCTED EMISSION

#### **Procedure of Preliminary Test**

• The EUT was set up as per the test configuration to simulate typical usage per the user's manual. When the EUT is a tabletop system, a wooden table with a height of 0.8 meters is used and is placed on the ground plane as per EN 55022 (see Test Facility for the dimensions of the ground plane used). When the EUT is a floor-standing equipment, it is placed on the ground plane which has a 3-12 mm non-conductive covering to insulate the EUT from the ground plane.

Date of Issue: January 6, 2005

- Support equipment, if needed, was placed as per EN 55022.
- All I/O cables were positioned to simulate typical actual usage as per EN 55022.
- The test equipment EUT installed received AC power, 230VAC/50Hz, through a Line Impedance Stabilization Network (LISN), which supplied power source and was grounded to the ground plane.
- All support equipment received power from a second LISN.
- The EUT test program was started. Emissions were measured on each current carrying line of the EUT using an EMI Test Receiver connected to the LISN powering the EUT.
- The Receiver scanned from 150kHz to 30MHz for emissions in each of the test modes.
- During the above scans, the emissions were maximized by cable manipulation.
- The test mode(s) described in Item 3.2 were scanned during the preliminary test.
- After the preliminary scan, we found the test mode described in Item 3.2 producing the highest emission level.
- The EUT configuration and cable configuration of the above highest emission level were recorded for reference of the final test.

#### **Procedure of Final Test**

- EUT and support equipment were set up on the test bench as per the configuration with highest emission level in the preliminary test.
- A scan was taken on both power lines, Line 1 and Line 2, recording at least the six highest emissions. Emission frequency and amplitude were recorded into a computer in which correction factors were used to calculate the emission level and compare reading to the applicable limit. If EUT emission level was less –2dB to the Average limit in Q.P. mode, then the emission signal was re-checked using an Average detector.
- The test data of the worst-case condition(s) was recorded.

Page 12 Rev. 00

#### **Data Sample:**

Freq. (MHz)	Q.P. Raw (dBuV)	Average Raw (dBuV)	Q.P. Limit (dBuV)	Average Limit (dBuV)	Q.P. Margin (dB)	Average Margin (dB)	Note
X.XX	43.95		56.00	46.00	-12.05		L1

Date of Issue: January 6, 2005

Freq. = Emission frequency in MHz

Raw dBuV = Uncorrected Analyzer/Receiver reading + Insertion loss of LISN, if it > 0.5 dB

Limit dBuV = Limit stated in standard

Margin dB = Reading in reference to limit Note = Current carrying line of reading

"---" = The emission level complied with the Average limits, with at least 2dB margin

limits, so no further recheck.

#### **Calculation Formula**

Margin (dB) = RAW (dBuV) - Limit (dBuV)

# 7.3 TEST PROCEDURE OF COMMON MODE CONDUCTED EMISSION FOR TELECOMMUNICATION PORT

- Selecting ISN for unscreened cable or a current probe for screened cable to take measurement.
- The port of the EUT was connected to the remote side support equipment through the ISN/Current Probe and communication in normal condition.
- Making a overall range scan by using the test receiver controlled by controller and record at least six highest emissions for showing in the test report.
- Emission frequency and amplitude were recorded into a computer in which correction factors were used to calculate the emission level and compare reading to the applicable limit.
- In case of measuring on the screened cable, the current limit shall be applied, otherwise the voltage limit should be applied.
- The following test mode(s) were scanned during the preliminary test:

No applicable, because EUT hasn't LAN Port or Modem Port.

Page 13 Rev. 00

#### **Data Sample:**

Freq. (MHz)	Q.P. Raw (dBuV)	AV. Raw (dBuV)	Q.P. Limit (dBuV)	AV. Limit (dBuV)	Q.P. Margin (dB)	AV. Margin (dB)	Note
x.xx	43.95		74.00	64.00	-30.05		

Date of Issue: January 6, 2005

Freq.: Emission frequency

Raw: Uncorrected Analyzer / Receiver reading

Limit: Limit stated in standard

Margin: Reading in reference to limit

Note: Current carrying line of reading

"-": The emission level complied with the Average limits, with at least 2 dB margin,

so no further recheck.

#### 7.4 TEST PROCEDURE OF RADIATED EMISSION

#### **Procedure of Preliminary Test**

- The equipment was set up as per the test configuration to simulate typical usage per the user's manual. When the EUT is a tabletop system, a wooden turntable with a height of 0.8 meters is used which is placed on the ground plane. When the EUT is a floor-standing equipment, it is placed on the ground plane which has a 3-12 mm non-conductive covering to insulate the EUT from the ground plane.
- Support equipment, if needed, was placed as per EN 55022.
- All I/O cables were positioned to simulate typical usage as per EN 55022.
- The EUT received AC power source, 230VAC/50Hz, from the outlet socket under the turntable. All support equipment received power from another socket under the turntable.
- The antenna was placed at 10 meter away from the EUT as stated in EN 55022. The antenna connected to the Spectrum Analyzer via a cable and at times a pre-amplifier would be used.
- The Analyzer / Receiver quickly scanned from 30MHz to 1000MHz. The EUT test program was started. Emissions were scanned and measured rotating the EUT to 360 degrees and positioning the antenna 1 to 4 meters above the ground plane, in both the vertical and the horizontal polarization, to maximize the emission reading level.
- The test mode(s) described in Item 3.2 were scanned during the preliminary test:
- After the preliminary scan, we found the test mode described in Item 3.2 producing the highest emission level.
- The EUT and cable configuration, antenna position, polarization and turntable position of the above highest emission level were recorded for the final test.

Page 14 Rev. 00

#### **Procedure of Final Test**

• EUT and support equipment were set up on the turntable as per the configuration with highest emission level in the preliminary test.

Date of Issue: January 6, 2005

- The Analyzer / Receiver scanned from 30MHz to 1000MHz. Emissions were scanned and measured rotating the EUT to 360 degrees, varying cable placement and positioning the antenna 1 to 4 meters above the ground plane, in both the vertical and the horizontal polarization, to maximize the emission reading level.
- Recorded at least the six highest emissions. Emission frequency, amplitude, antenna position, polarization and turntable position were recorded into a computer in which correction factors were used to calculate the emission level and compare reading to the applicable limit and only Q.P. reading is presented.
- The test data of the worst-case condition(s) was recorded.

#### **Data Sample:**

Freq. (MHz)	Raw Data (dBuV)	Corr. Factor (dB/m)	Emiss. Level (dBuV/m)	Limits (dBuV/m)	Margin (dB)
XX.XX	14.00	12.20	26.20	30.00	-3.80

Freq. = Emission frequency in MHz

Raw Data (dBuV) = Uncorrected Analyzer / Receiver reading
Corr. Factor (dB/m) = Antenna factor + Cable loss – Amplifier gain
Emiss. Level (dBuV/m) = Raw reading converted to dBuV/m and CF added

Limit (dBuV/m) = Limit stated in standard Margin (dB) = Reading in reference to limit

P = Peak Reading
Q = Quasi-peak Reading
A = Average Reading

#### **Calculation Formula**

Margin (dB) = Emiss. Level (dBuV/m) – Limits (dBuV/m) Emission Level (dBuV/m) = Raw Data (dBuV) + Corr. Factor (dB/m)

Page 15 Rev. 00

#### 7.5 TEST RESULTS

#### **Line Conducted Emission**

**Model:** FPM-3171GA-R **Test Mode:** Mode 1

**Temperature:** 18°C **Humidity:** 58% RH

**Tested by:** Carl Chang **Test Results:** Pass

(The chart below shows the highest readings taken from the final data)

Freq. (MHz)	Q.P. Raw (dBuV)	AVG Raw (dBuV)	Q.P. Limit (dBuV)	AVG Limit (dBuV)	Q.P. Margin (dB)	AVG Margin (dB)	NOTE
0.180	44.10		64.49	54.49	-20.39		L1
1.148	28.30		56.00	46.00	-27.70		L1
3.029	27.70		56.00	46.00	-28.30		L1
4.358	33.40		56.00	46.00	-22.60		L1
5.798	20.00		60.00	50.00	-40.00		L1
8.471	21.60		60.00	50.00	-38.40		L1
0.180	43.60		64.49	54.49	-20.89		L2
1.329	25.10		56.00	46.00	-30.90		L2
3.328	28.40		56.00	46.00	-27.60		L2
4.609	29.30		56.00	46.00	-26.70		L2
6.298	23.50		60.00	50.00	-36.50		L2
7.029	23.70		60.00	50.00	-36.30		L2

L1 = Line One (Live Line) / L2 = Line Two (Neutral Line)

Note: "---" denotes the emission level was or more than 2dB below the Average limit, so no re-check anymore.

#### **Common Mode Conducted Emission**

Not applicable

Page 16 Rev. 00

### **Radiated Emission (A)**

**Model:** FPM-3171GA-R **Test Mode:** Mode 1

**Temperature:** 20°C **Humidity:** 61% RH

**Detector Function:** Quasi-peak. **Antenna:** Vertical at 10m

**Tested by:** Ken Jung **Test Results:** Pass

(The chart below shows the highest readings taken from the final data)

Freq.	Raw	Corr.	Emiss.	Limits	Margin
(MHz)	Data (dBuV)	Factor (dB/m)	Level (dBuV/m)	(dBuV/m)	(dB)
112.60	15.1	12.7	27.8	30.0	-2.2
116.46	11.7	13.2	24.9	30.0	-5.1
159.66	11.8	15.1	26.9	30.0	-3.1
233.51	16.5	13.1	29.6	37.0	-7.4
432.94	9.0	19.1	28.1	37.0	-8.9
569.46	5.5	23.1	28.6	37.0	-8.4
679.80	6.3	24.4	30.7	37.0	-6.3

Page 17 Rev. 00

### **Radiated Emission (B)**

**Model:** FPM-3171GA-R **Test Mode:** Mode 1

**Temperature:** 20°C **Humidity:** 61% RH

**Detector Function:** Quasi-peak. **Antenna:** Horizontal at 10m

**Tested by:** Ken Jung **Test Results:** Pass

(The chart below shows the highest readings taken from the final data)

Freq.	Raw	Corr.	Emiss.	Limits	======= Margin
(MHz)	Data (dBuV)	Factor (dB/m)	Level (dBuV/m)	(dBuV/m)	(dB)
109.69	13.2	12.3	25.5	30.0	-4.5
200.31	9.2	11.8	21.0	30.0	-9.0
232.84	14.3	13.1	27.4	37.0	-9.6
299.27	14.6	15.6	30.2	37.0	-6.8
569.26	7.7	23.1	30.8	37.0	-6.2
643.26	4.5	24.0	28.5	37.0	-8.5
732.33	4.5	25.3	29.8	37.0	-7.2

Page 18 Rev. 00

# 8 POWER HARMONICS TEST

**Port** : AC mains

**Basic Standard** : EN 61000-3-2 (2000)

Limits :  $\Box$  CLASS A;  $\Box$  CLASS B;  $\Box$  CLASS C;  $\Box$  CLASS D

**Tested by** : Carl Chang

**Temperature** : 20°C **Humidity** : 57%

# **Limit:**

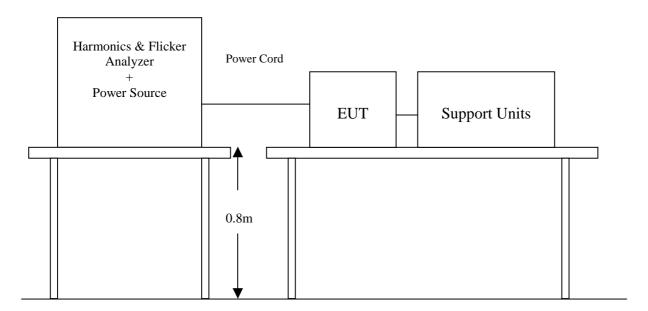
Limits for Class A equipment				
Harmonics	Max. permissible			
Order	harmonics current			
n	A			
Od	ld harmonics			
3	2.30			
5	1.14			
7	0.77			
9	0.40			
11	0.33			
13	0.21			
15<=n<=39	0.15x15/n			
Eve	en harmonics			
2	1.08			
4	0.43			
6	0.30			
8<=n<=40	0.23x8/n			

	Limits for Class D equipment						
Harmonics Order n	Max. permissible harmonics current per watt mA/W	Max. permissible harmonics current					
	Odd Harmonics only	/					
3	3.4	2.30					
5	1.9	1.14					
7	1.0	0.77					
9	0.5	0.40					
11	0.35	0.33					
13	0.30	0.21					
15<=n<=39	3.85/n	0.15x15/n					

Date of Issue: January 6, 2005

Page 19 Rev. 00

## **Block Diagram of Test Setup:**



Date of Issue: January 6, 2005

### **Test Procedure:**

- a. The EUT was placed on the top of a wooden table 0.8 meters above the ground and operated to produce the maximum harmonic components under normal operating conditions for each successive harmonic component in turn.
- b. The correspondent test program of test instrument to measure the current harmonics emanated from EUT is chosen. The measure time shall be not less than the time necessary for the EUT to be exercised.

<u>Test Result</u>: (See Appendix II for details)

EUT max Power: 33.286W

**Note:** According to clause 7 of EN 61000-3-2: 2000, equipment with a rated power of 75W or less, no limits apply.

Page 20 Rev. 00

# 9 POWER VOLTAGE FLUCTUATION / FLICKER TEST

Date of Issue: January 6, 2005

**Port** : AC mains

**Basic Standard** : EN 61000-3-3 (1995 + A1: 2001)

**Limits** : §5 of EN 61000-3-3

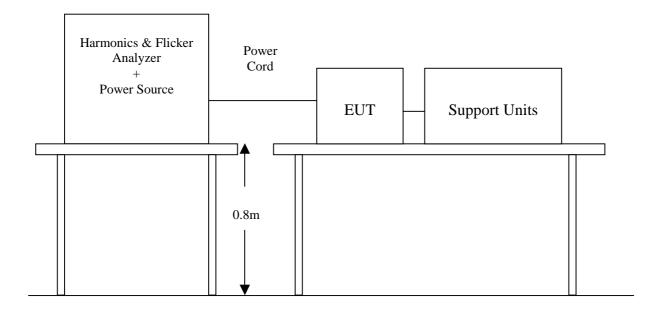
**Tested by** : Carl Chang

**Temperature** : 26°C **Humidity** : 55%

# **Limit:**

TEST ITEM	LIMIT	REMARK
$P_{st}$	1.0	P <sub>st</sub> means short-term flicker indicator.
$P_{lt}$	0.65	P <sub>lt</sub> means long-term flicker indicator.
T <sub>dt</sub> (ms)	500	$T_{dt}$ means maximum time that dt exceeds 3 %.
d <sub>max</sub> (%)	4%	d <sub>max</sub> means maximum relative voltage change.
dc (%)	3.3%	dc means relative steady-state voltage change

# **Block Diagram of Test Setup:**



Page 21 Rev. 00

## **Test Procedure:**

a. The EUT was placed on the top of a wooden table 0.8 meters above the ground and operated to produce the most unfavorable sequence of voltage changes under normal operating conditions.

Date of Issue: January 6, 2005

b. During the flick measurement, the measure time shall include that part of whole operation cycle in which the EUT produce the most unfavorable sequence of voltage changes. The observation period for short-term flicker indicator is 10 minutes and the observation period for long-term flicker indicator is 2 hours.

**Test Result:** (See Appendix II for details)

#### **Continue**

Test Parameter	Measurement Value	Limit	Result
$P_{st}$	0.072	1.0	Pass
$P_{lt}$	0.072	0.65	Pass
T <sub>dt</sub> (ms)	0	500	Pass
d <sub>max</sub> (%)	0%	4%	Pass
dc (%)	0%	3.3%	Pass

#### **Manual Switch**

Test Parameter	Measurement Value	Limit	Result
$P_{st}$	0.072	1.0	Pass
$P_{lt}$	0.072	0.65	Pass
T <sub>dt</sub> (ms)	0	500	Pass
d <sub>max</sub> (%)	0%	4%	Pass
dc (%)	0%	3.3%	Pass

Page 22 Rev. 00

# 10 ELECTROSTATIC DISCHARGE (ESD) IMMUNITY TEST

Date of Issue: January 6, 2005

**Port** : Enclosure

**Basic Standard**: IEC/EN 61000-4-2

**Test Level** :  $\pm 8 \text{ kV (Air Discharge)}$ 

± 4 kV (Contact Discharge)

± 4 kV (Indirect Discharge)

**Performance Criterion**: B (Standard Required)

**Tested by** : Carl Chang

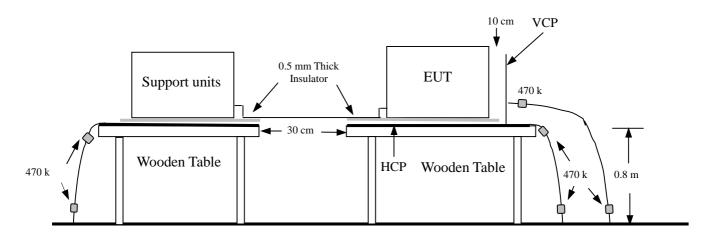
**Temperature** : 22°C

**Humidity** : 50% RH

**Pressure**: 1019mbar

## **Block Diagram of Test Setup:**

(The 470 k ohm resistors are installed per standard requirement.)



**Ground Reference Plane** 

Page 23 Rev. 00

#### **Test Procedure:**

- 1. The EUT was located 0.1 m minimum from all side of the HCP.
- 2. The indirect support units were located 1 m minimum away from the EUT, but direct support unit was/were located at same location as EUT on the HCP and keep at a distance of 10 cm with EUT.
- 3. A scroll 'H' test program was loaded and executed in Windows XP mode.
- 4. The Host PC sent above message to EUT and related peripherals through the test.
- 5. Active the communication function if the EUT with such port(s).
- 6. As per the requirement of EN 55024; applying direct contact discharge at the sides other than front of EUT at minimum 50 discharges (25 positive and 25 negative) if applicable, can't be applied direct contact discharge side of EUT then the indirect discharge shall be applied. One of the test points shall be subjected to at least 50 indirect discharge (contact) to the front edge of horizontal coupling plane.

Date of Issue: January 6, 2005

- 7. Other parts of EUT where it is not possible to perform contact discharge then selecting appropriate points of EUT for air discharge, a minimum of 10 single air discharges shall be applied.
- 8. The application of ESD to the contact of open connectors is not required.
- 9. The EUT direct connection units also need to be applied ESD at the port of EUT cable connected.
- 10. Putting a mark on EUT to show tested points. The following test condition was followed during the tests.

**Note:** As per IEC/EN 61000-4-2, two 470k bleed resistors cable is connected between the EUT and HCP during the test applicable for power ungrounded or battery operating unit only.

The electrostatic discharges were applied as follows:

Amount of discharge	Voltage	Coupling	Result (Pass/Fail)
Mini 10 /Point	$\pm~8~kV$	Air Discharge	Pass
Mini 25 /Point	$\pm 4 \text{ kV}$	Contact Discharge	Pass
Mini 25 /Point	$\pm 4 \text{ kV}$	Indirect Discharge HCP	Pass
Mini 25 /Point	$\pm 4 \text{ kV}$	Indirect Discharge VCP (Right)	Pass
Mini 25 /Point	± 4 kV	Indirect Discharge VCP (Left)	Pass
Mini 25 /Point	$\pm 4 \text{ kV}$	Indirect Discharge VCP (Back)	Pass

For the tested points to EUT, please refer to attached page.

(Blue arrow mark for Contact Discharge and red arrow mark for Air Discharge)

Page 24 Rev. 00

# **Performance & Result:**

Criteria A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
Criteria B:	The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
Criteria C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.
<b>Observation:</b> N	No function degraded during the tests.

Date of Issue: January 6, 2005

Page 25 Rev. 00

# The Tested Points of EUT

# Photo 1 of 5



Photo 2 of 5



Page 26 Rev. 00

Photo 3 of 5



Photo 4 of 5



Page 27 Rev. 00

# Photo 5 of 5



Page 28 Rev. 00

# 11 RADIATED ELECTROMAGNETIC FIELD IMMUNITY TEST

Date of Issue: January 6, 2005

**Port** : Enclosure

**Basic Standard**: IEC/EN 61000-4-3

**Requirements** : 3 V/m / with 80% AM. 1kHz Modulation.

**Performance Criterion**: A (Standard Required)

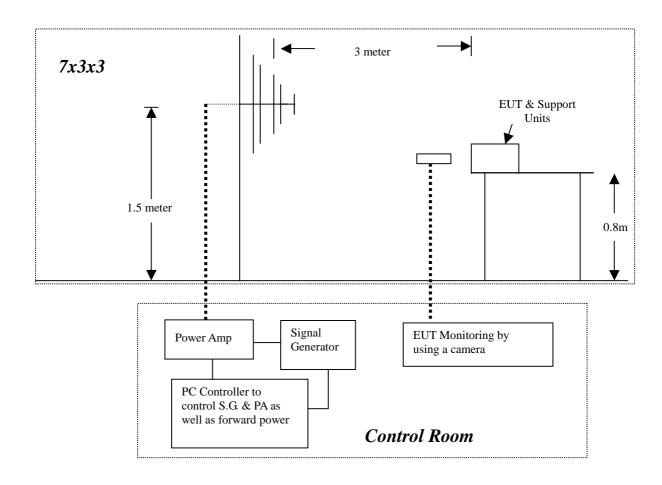
**Tested by** : Carl Chang

**Temperature** : 22°C

**Humidity** : 50% RH

**Pressure**: 1019mbar

# **Block Diagram of Test Setup:**



Page 29 Rev. 00

# **Test Procedure:**

1. The EUT was located at the edge of supporting table keep 3 meter away from transmitting antenna, it just the calibrated square area of field uniformity. The support units were located outside of the uniformity area, but the cable(s) connected with EUT were exposed to the calibrated field as per IEC/EN 61000-4-3.

Date of Issue: January 6, 2005

- 2. Setting the testing parameters of RS test software per IEC/EN 61000-4-3.
- 3. Performing the pre-test at each side of with double specified level (6V/m) at 4% steps.
- 4. From the result of pre-test in step 5, choice the worst side of EUT for final test from 80 MHz to 1000 MHz at 1% steps.
- 5. Recording the test result in following table.
- 6. It is not necessary to perform test as per annex A of EN 55024 if the EUT doesn't belong to ITE product.

#### **Preliminary test conditions:**

Test level : 6V/m

Steps : 4 % of fundamental

Dwell Time : 3 sec

Range (MHz)	Field	Modulation	Polarity	Position	Result (Pass/Fail)
80-1000	6V/m	Yes	Н	Front	Pass
80-1000	6V/m	Yes	V	Front	Pass
80-1000	6V/m	Yes	Н	Right	Pass
80-1000	6V/m	Yes	V	Right	Pass
80-1000	6V/m	Yes	Н	Back	Pass
80-1000	6V/m	Yes	V	Back	Pass
80-1000	6V/m	Yes	Н	Left	Pass
80-1000	6V/m	Yes	V	Left	Pass

#### **Final test conditions:**

Test level : 3V/m

Steps : 1 % of fundamental

Dwell Time : 3 sec

Range (MHz)	Field	Modulation	Polarity	Position	Result (Pass/Fail)
80-1000	3V/m	Yes	Н	Front	Pass
80-1000	3V/m	Yes	V	Front	Pass

Page 30 Rev. 00

# **Performance & Result:**

Criteria A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.	
Criteria B:	The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.	
Criteria C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.	
Observation: No function degraded during the tests.		

Date of Issue: January 6, 2005

Page 31 Rev. 00

## 12 FAST TRANSIENTS/BURST IMMUNITY TEST

**Port** : On Power Supply Line

**Basic Standard**: IEC/EN 61000-4-4

**Requirements** :  $\pm 1 \text{ kV}$  for Power Supply Line

Performance Criteria: B (Standard Required)

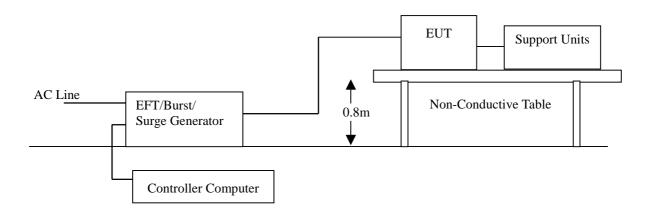
**Tested by** : Carl Chang

**Temperature** : 22°C

**Humidity** : 50% RH

**Pressure** : 1019mbar

# **Block Diagram of Test Setup:**



#### **Test Procedure:**

- 1. The EUT and support units were located on a wooden table 0.8 m away from ground reference plane.
- 2. A 1.0 meter long power cord was attached to EUT during the test.
- 3. The length of communication cable between communication port and clamp was keeping within 1 meter.
- 4. Injected test voltage to the EUT ports from minimum to standard request or client request.
- 5. Recording the test result as shown in following table.

Page 32 Rev. 00

#### **Test conditions:**

Impulse Frequency: 5kHz
Tr/Th:: 5/50ns
Burst Duration:: 15ms
Burst Period:: 3Hz

Inject Line	Voltage kV	Inject Method	Result (Pass/Fail)
L	± 1	Direct	Pass
N	± 1	Direct	Pass
PE	± 1	Direct	Pass
L+N	± 1	Direct	Pass
L + PE	± 1	Direct	Pass
N + PE	± 1	Direct	Pass
L + N + PE	± 1	Direct	Pass

Date of Issue: January 6, 2005

# **Performance & Result:**

Criteria A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.	
Criteria B:	The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.	
Criteria C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.	
Observation: No function degraded during the tests.		

Page 33 Rev. 00

# 13 SURGE IMMUNITY TEST

**Port** : Power Cord

**Basic Standard**: IEC/EN 61000-4-5

**Requirements** :  $\pm 1 \text{ kV}$  (Line to Line)

 $\pm 2$  kV (Line to Ground)

Date of Issue: January 6, 2005

**Performance Criteria**: B (Standard Required)

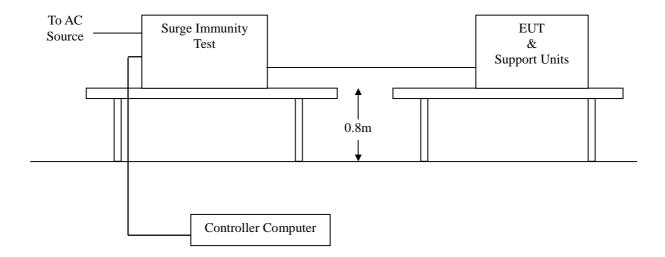
**Tested by** : Carl Chang

**Temperature** : 22°C

**Humidity** : 50% RH

Pressure : 1019mbar

# **Block Diagram of Test Setup:**



# **Test Procedure:**

- 1. The EUT and support units were located on a wooden table 0.8 m away from ground floor.
- 2. Injected test voltage to the EUT ports from minimum to standard request or client request.
- 3. Recording the test result as shown in following table.

Page 34 Rev. 00

#### **Test conditions:**

Voltage Waveform : 1.2/50 us Current Waveform: 8/20 us

Polarity : Positive/Negative Phase angle : 0°, 90°, 270° Number of Test : 5

Coupling Line	Voltage (kV)	Polarity	Coupling Method	Result (Pass/Fail)
L1-L2	1	Positive	Capacitive	Pass
L1-PE	2	Positive	Capacitive	Pass
L2-PE	2	Positive	Capacitive	Pass
L1-L2	1	Negative	Capacitive	Pass
L1-PE	2	Negative	Capacitive	Pass
L2-PE	2	Negative	Capacitive	Pass

# **Performance & Result:**

Criteria A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.	
Criteria B:	The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.	
Criteria C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.	
Observation: No function degraded during the tests.		

Page 35 Rev. 00

# 14 CONDUCTED DISTURBANCE/INDUCED RADIO-FREQUENCY FIELD IMMUNITY TEST

**Port** : AC Port

**Basic Standard**: IEC/EN 61000-4-6

**Requirements** : 3 V with 80% AM. 1kHz Modulation.

**Injection Method** : CDN-M3 for Power Cord

**Performance Criterion**: A (Standard Required)

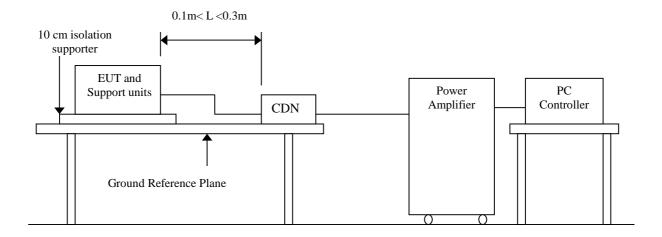
**Tested by** : Roger Wu

**Temperature** : 22°C

**Humidity** : 50% RH

Pressure : 1019mbar

# **Block Diagram of Test Setup:**



#### **Test Procedure:**

- 1. The EUT and support units were located at a ground reference plane with the interposition of a 0.1 m thickness insulating support and the CDN was located on GRP directly.
- 2. Setting the testing parameters of CS test software as per IEC/EN 61000-4-6.
- 3. Recording the test result in following table.

Page 36 Rev. 00

### **Test conditions:**

Frequency Range : 0.15MHz-80MHz
Frequency Step : 1% of fundamental

Dwell Time : 3 sec

Range (MHz)	Field	Modulation	Result (Pass/Fail)
0.15-80	3V	Yes	Pass

Date of Issue: January 6, 2005

# **Performance & Result:**

Criteria A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.		
Criteria B:	The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.		
Criteria C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.		
Observation: No function degraded during the tests.			

Page 37 Rev. 00

# 15 POWER FREQUENCY MAGNETIC FIELD IMMUNITY TEST

Date of Issue: January 6, 2005

**Port** : Enclosure

**Basic Standard**: IEC/EN 61000-4-8

**Requirements** : 1 A/m

**Performance Criterion**: A (Standard Required)

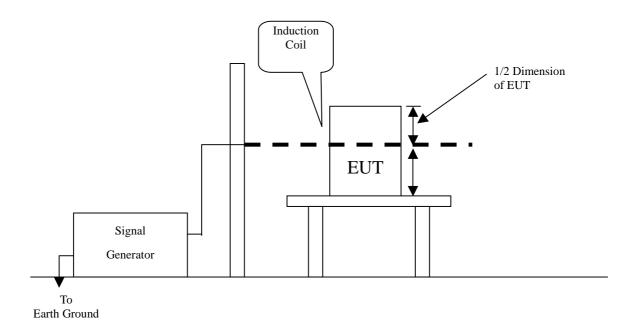
**Tested by** : Carl Chang

**Temperature** : 22°C

**Humidity** : 50% RH

**Pressure**: 1019mbar

## **Block Diagram of Test Setup:**



### **Test Procedure:**

- 1. The EUT and support units were located on Ground Reference Plane with the interposition of a 0.1 m thickness insulation support.
- 2. Putting the induction coil on horizontal direction. ( X direction )
- 3. Rotating the induction coil by 90° (Y direction)
- 4. Rotating the induction coil by 90° again ( Z direction )
- 5. Recording the test result as shown in following table.

Page 38 Rev. 00

### **Test conditions:**

Field Strength: 1A/m Power Freq.: 50Hz Orientation: X, Y, Z

Orientation	Field	Result (Pass/Fail)	Remark
X	1A/m	Pass	
Y	1A/m	Pass	
Z	1A/m	Pass	

Date of Issue: January 6, 2005

# **Performance & Result:**

Criteria A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.		
Criteria B:	The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.		
Criteria C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.		
<b>Observation:</b> No function degraded during the tests.			

Page 39 Rev. 00

### 16 VOLTAGE DIPS / SHORT INTERRUPTIONS

**Port** : AC mains

**Basic Standard**: IEC/EN 61000-4-11

**Requirement**: PHASE ANGLE 0, 45, 90, 135, 180, 225, 270, 315 degrees

Voltage	Test Level % U <sub>T</sub>	Reduction (%)	Duration ( periods )	Performance Criteria
Dips	<5	>95	0.5	В
	70	30	25	С

Date of Issue: January 6, 2005

Voltage Interceptions	Test Level % U <sub>T</sub>	Reduction (%)	Duration ( periods )	Performance Criteria
	<5	>95	250	С

**Test Interval** : Min. 10 sec.

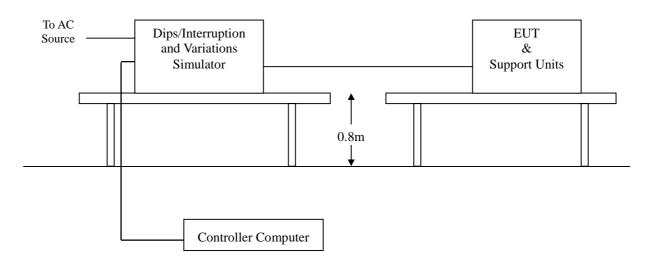
**Tested by** : Carl Chang

**Temperature** : 22°C

**Humidity** : 50% RH

**Pressure**: 1019mbar

## **Block Diagram of Test Setup:**



### **Test Procedure:**

- 1. The EUT and support units were located on a wooden table, 0.8 m away from ground floor.
- 2. Setting the parameter of tests and then Perform the test software of test simulator.
- 3. Conditions changes to occur at 0 degree crossover point of the voltage waveform.
- 4. Recording the test result in test record form.

Page 40 Rev. 00

#### **Test conditions**

The duration with a sequence of three dips/interruptions with interval of 10 s minimum (Between each test event)

### **Voltage Dips:**

est Level % U <sub>T</sub>	Reduction (%)	Duration (periods)	Observation	Meet Performance Criteria
0	100	0.5	Normal	A
70	30	25	Normal	A

Date of Issue: January 6, 2005

## **Voltage Interruptions:**

Test Level % U <sub>T</sub>	Reduction (%)	Duration (periods)	Observation	Meet Performance Criteria
0	100	250	EUT shut down, but can be auto recovered as the events disappear.	

Normal: No any functions degrade during and after the test.

# **Performance & Result:**

Criteria A:	The apparatus continues to operate as intended. No degradation of
	performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
Criteria B:	The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
Criteria C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.

Page 41 Rev. 00

# APPENDIX I - PHOTOGRAPHS OF TEST SETUP

# LINE CONDUCTED EMISSION TEST (EN 55022)





Page 42 Rev. 00

# **RADIATED EMISSION TEST (EN 55022)**





Page 43 Rev. 00

POWER HARMONIC & VOLTAGE FLUCTUATION / FLICKER TEST

Date of Issue: January 6, 2005



Page 44 Rev. 00

## ELECTROSTATIC DISCHARGE TEST





Page 45 Rev. 00

## RADIATED ELECTROMAGNETIC FIELD TEST



## FAST TRANSIENTS/BURST TEST



Page 46 Rev. 00

## **SURGE IMMUNITY TEST**



# CONDUCTED DISTURBANCE, INDUCED BY RADIO-FREQUENCY FIELDS TEST



Page 47 Rev. 00

## POWER FREQUENCY MAGNETIC FIELD IMMUNITY TEST



### **VOLTAGE DIPS / INTERRUPTION TEST**



Page 48 Rev. 00

## APPENDIX II - TEST RESULT OF EN 61000-3-3

ADVANTECH Date: 2005/1/3 PM 11:37:01 V3.15

File :

Operator : CARL

EUT: LCD MONITOR
Model No. FPM-3171GA-R

Remarks TEMP:26 HUMD:55 (Continue)

Urms = 230.1V Freq = 49.987 Range: 2 A Irms = 0.320A Ipk = 1.368A cf = 4.271P = 32.49W Pap = 73.71VA pf = 0.441

Test - Time :  $1 \times 10min = 10min$  ( 100 %)

LIN (Line Impedance Network): SLIN 0.24ohm +j0.15ohm N:0.16ohm +j0.10ohm

Limits :Plt : 0.65 Pst : 1.00

dmax : 4.00 % dc : 3.30 %

dtLim: 3.30 % dt>Lim: 500ms

Test completed, Result: PASSED

Plt = 0.072

Pst dmax dc dt>Lim Fail

[%] [%] [ms]

1 0.072 0.000 0.000 0.000

Page 49 Rev. 00

Date of Issue: January 6, 2005

COMPAL Date: 2005/1/4 AM 12:11:18 V3.15

Date of Issue: January 6, 2005

File :

Operator: CARL

EUT: LCD MONITOR Model No. FPM-3171GA-R

Remarks TEMP:26 HUMD:55 (Manual Switch)

Urms = 230.1V Freq = 49.987 Range: 2 A Irms = 0.319A Ipk = 1.376A cf = 4.309P = 32.00W Pap = 73.48VA pf = 0.436

Test - Time :  $1 \times 10min = 10min$  ( 100 %)

LIN (Line Impedance Network) : SLIN 0.24ohm +j0.15ohm N:0.16ohm +j0.10ohm

Limits :Plt : 0.65 Pst : 1.00

dmax : 4.00 % dc : 3.30 %

dtLim: 3.30 % dt>Lim: 500ms

Test completed, Result: PASSED

Plt = 0.072

Pst dmax dc dt>Lim Fail

[%] [%] [ms]

1 0.072 0.000 0.000 0.000

Page 50 Rev. 00